

Notice of References Cited

Application/Control No.

09/994,395

Applicant(s)/Patent Under
Reexamination
LOPATIN ET AL.

Examiner

Thomas J. Magee

Art Unit

2811

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,399,496 B1 ✓	06-2002	Daniel Charles Edelstein et al.	438/687
	B	US-5,243,222 ✓	09-1993	James M. E. Harper et al.	257/774
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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✓	U	James A. Cunningham, "Improving Copper Interconnects: A Search for Useful Dopants," Semiconductor International, (April. 2000), pp. 1-8.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.